## Supporting Information for "Superconductivity and Magnetotransport of Single-Crystalline NbSe<sub>2</sub> Nanoplates Grown by Chemical Vapour Deposition"

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**Fig. S1** (a) Magnified view of the XRD pattern shown in Fig. 1c, with all the major peaks indexed as the 2H NbSe<sub>2</sub>. (b) Raman spectrum taken from the NbSe<sub>2</sub> nanoplate, in which the prominent features observed at ~228 cm<sup>-1</sup> ( $A_{1g}$  mode) and ~238 cm<sup>-1</sup> ( $E_{2g}$  mode) are consistent with the previous reported Raman spectra of NbSe<sub>2</sub>.<sup>1,2</sup> (c) Magnified view of the EDS spectrum shown in Fig. 2b, confirming that there was no detectable impurity elements in the as-grown nanoplate.



**Fig. S2** (a) BF TEM image taken from another typical NbSe<sub>2</sub> nanoplate (sample 2#). (b) SAED pattern taken along [0001] axis. (c) EDS point profile taken from the nanoplate (please note that Cu peaks are due to the copper grid used for supporting the samples). (d) Atomic-resolution HAADF-STEM image taken from the nanoplate along [0001].

## References

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